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(54) PRODUCT INSPECTING APPARATUS WITH THERMOGRAPHY

(57) Abstract:

PROBLEM TO BE SOLVED: To improve accuracy in detecting failures of a heat-sealed product having a temperature distribution including a high temperature region and a low temperature region by acquiring detection signals of an infrared camera in a predetermined measurement range in a direction for carrying, counting signals at an abnormal temperature level while comparing with a determination value at the abnormal temperature level and comparing the count with a determination value of a defective product.

SOLUTION: An infrared camera 12 line-scans objects to be inspected which have been heat-sealed and cut into a product unit by a heat-sealer 11 for outputting a temperature measurement signal tm , and the temperature measurement signal tm is compared in a level determination part 14 with determination values TA , TB , TC stored in a determination value register 18 for de-

termining a level. Respective temperature measurement signals tm whose level have been determined are counted by a level counting part 15, and the respective counts nA , nB , nC are held in a counter 19. A defective product determination part 16 compares the counts nA , nB , nC counted by the level counting part 15 with the respective determination values TA , TB , TC stored in a determination value register 20 for determining defective product. Determination signals are sent to a product processor 13.

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